

ABSTRACT

In order to find the positional relation between the reference coordinate system XY which defines the movement of a substrate W and the arrangement coordinate system $\alpha\beta$ which corresponds to a plurality of divided areas on the substrate W divided by street lines $S\alpha$ and $S\beta$, the substrate W and an observation field are moved relatively. By allowing position detecting method marks M_k on the substrate W to visit the observation field, the street lines $S\alpha$ and $S\beta$ are detected in the observation field during the observation field. According to the results of the detection, an approximate arrangement coordinate system is corrected. The positional relation between the reference coordinate system XY and the arrangement coordinate system $\alpha\beta$ is caught with high accuracy enough to allow the observation field to visit the position detection mark (M_k). Thus, by obtaining the arrangement coordinate system of the divided area in high speed with high accuracy, the highly precise exposure might be performed with improved throughput.